

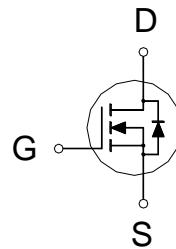
**NIKO-SEM**

# N-Channel Enhancement Mode Field Effect Transistor

**PB600BX**  
**PDFN 2x2S**  
**Halogen-Free & Lead-Free**

**PRODUCT SUMMARY**

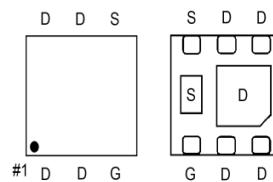
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub>
30V	12mΩ	10A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses.
- Ohmic Region Good R<sub>DS(on)</sub> Ratio.
- Optimized Gate Charge to Minimize Switching Losses.

**Applications**

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.
- Computer for DC to DC Converters Applications.



G : GATE  
D : DRAIN  
S : SOURCE

**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current	I <sub>D</sub>	10	A
		8.5	
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	27	
Avalanche Current	I <sub>AS</sub>	18	
Avalanche Energy	E <sub>AS</sub>	16.2	mJ
Power Dissipation <sup>3</sup>	P <sub>D</sub>	2.4	W
		1.5	
Operating Junction & Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	R <sub>θJA</sub>		52	°C/W
			71.7	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper.

<sup>3</sup>The Power dissipation is based on R<sub>θJA</sub> t ≤ 10s value.

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ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.3	1.75	2.3	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 9\text{A}$		12	17.5	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 9\text{A}$		9	12	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 10\text{V}, I_D = 9\text{A}$		48		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1\text{MHz}$		630		pF
Output Capacitance	$C_{\text{oss}}$			120		
Reverse Transfer Capacitance	$C_{\text{rss}}$			80		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		3.1		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g(V_{\text{GS}}=10\text{V})$	$V_{\text{DS}} = 15\text{V}, I_D = 9\text{A}$		13		nC
	$Q_g(V_{\text{GS}}=4.5\text{V})$			6.6		
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$			2.4		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			2.8		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$			6.8		nS
Rise Time <sup>2</sup>	$t_r$			49		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$			21		
Fall Time <sup>2</sup>	$t_f$			62		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				1.8	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = 9\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 9\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		7.5		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			2		nC

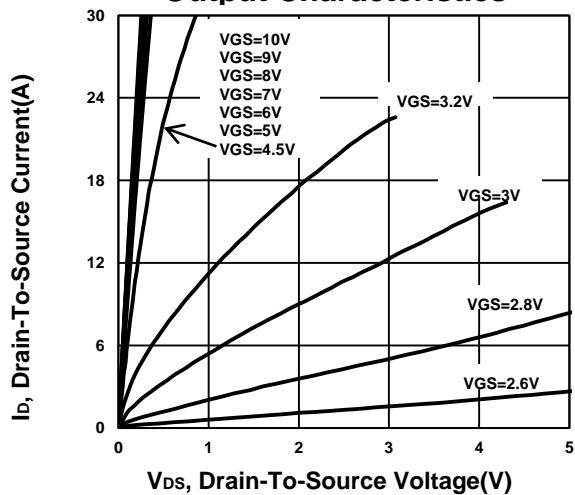
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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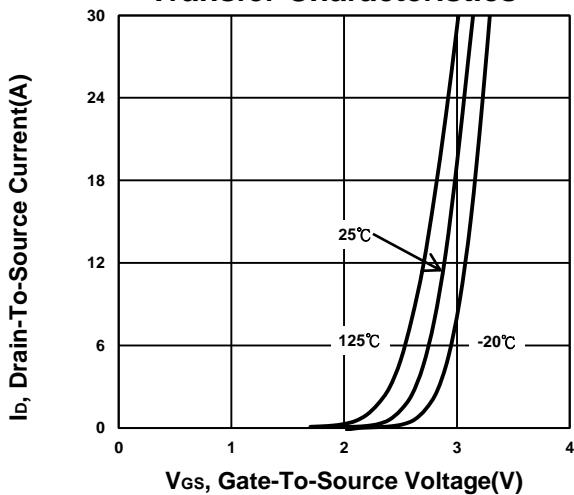
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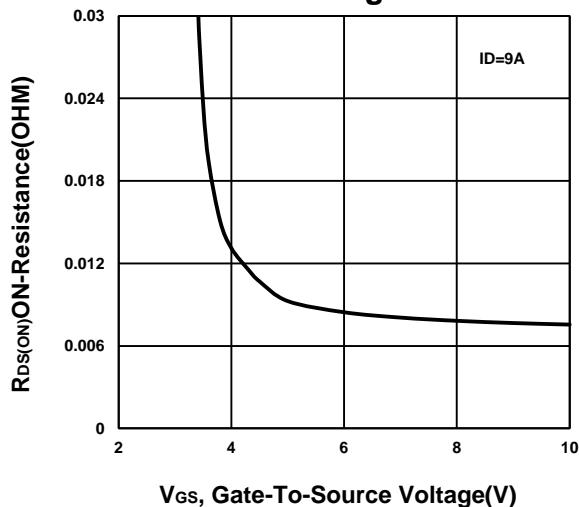
**Output Characteristics**



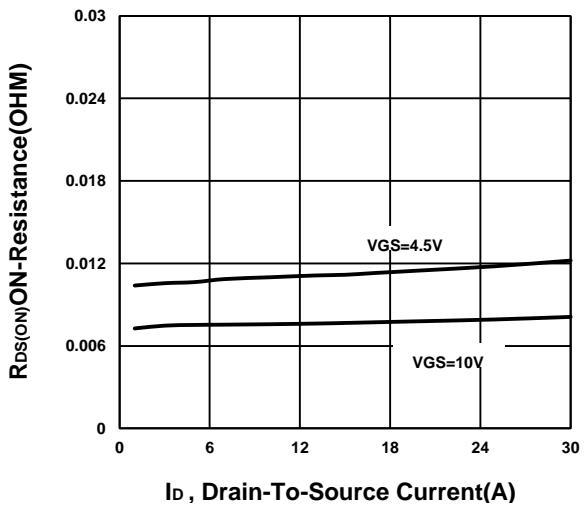
**Transfer Characteristics**



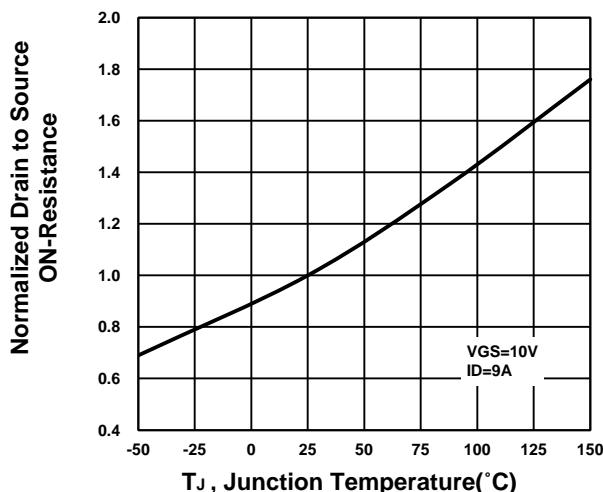
**On-Resistance VS Gate-To-Source Voltage**



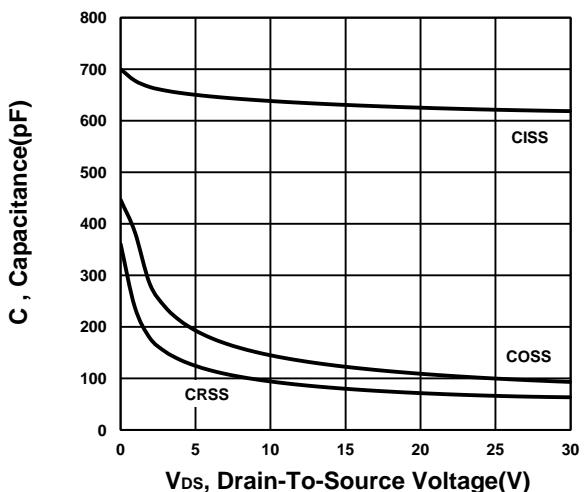
**On-Resistance VS Drain Current**



**On-Resistance VS Temperature**



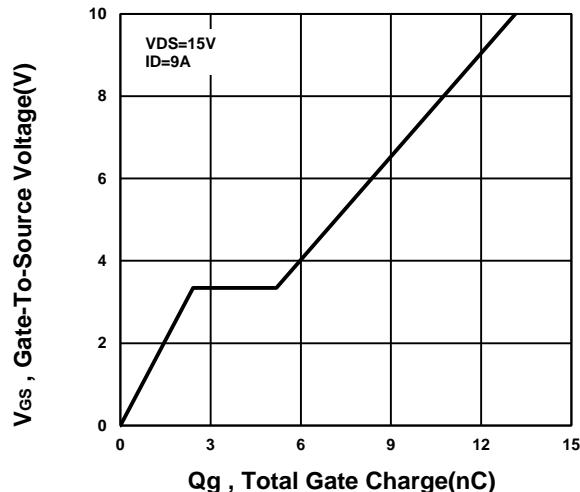
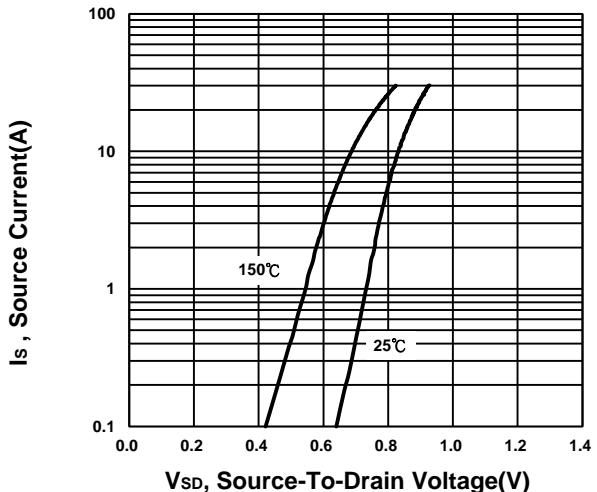
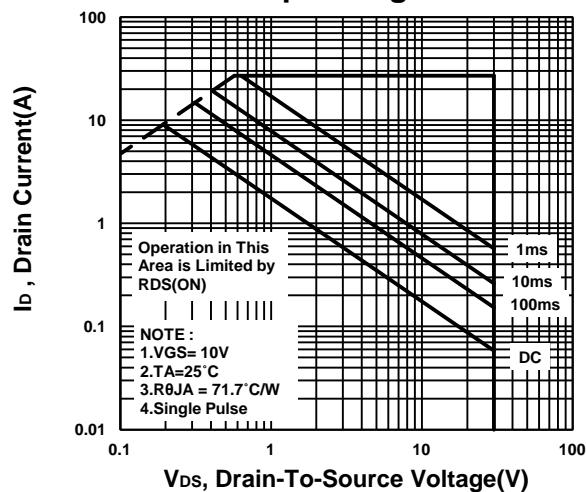
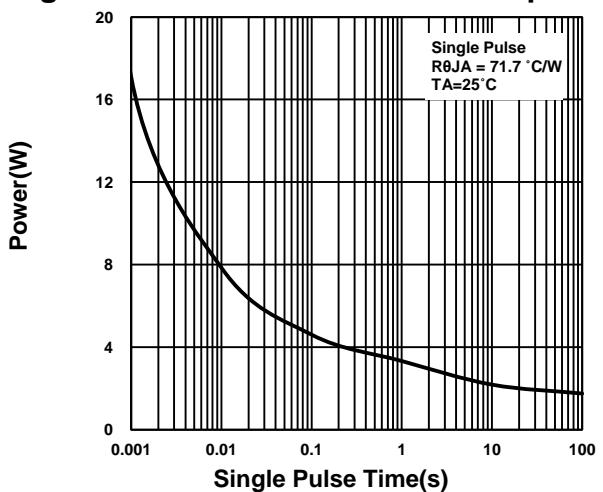
**Capacitance Characteristic**



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**Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**